

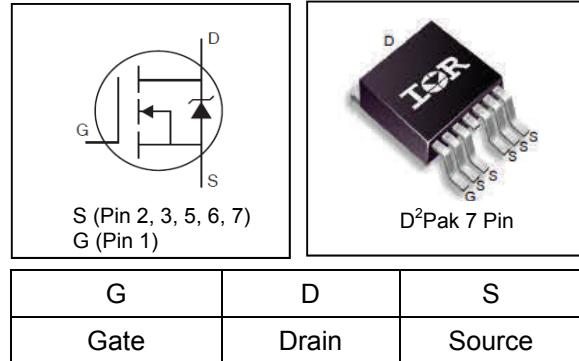
Features

- Advanced Process Technology
- Ultra Low On-Resistance
- 175°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to Tjmax
- Lead-Free, RoHS Compliant
- Automotive Qualified *

V_{DSS}	24V
$R_{DS(on)}$ typ.	0.8mΩ
	1.0mΩ
I_D (Silicon Limited)	429A①
I_D (Package Limited)	240A

Description

Specifically designed for Automotive applications, this HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in Automotive applications and wide variety of other applications.



G	D	S
Gate	Drain	Source

Base Part Number	Package Type	Standard Pack		Orderable Part Number
		Form	Quantity	
AUIRF1324S-7P	D²Pak 7 Pin	Tube	50	AUIRF1324S-7P

Absolute Maximum Ratings

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (TA) is 25°C, unless otherwise specified.

Symbol	Parameter	Max.	Units
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$ (Silicon Limited)	429①	A
$I_D @ T_C = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$ (Silicon Limited)	303①	
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$ (Package Limited)	240	
I_{DM}	Pulsed Drain Current ②	1640	
$P_D @ T_C = 25^\circ C$	Maximum Power Dissipation	300	W
	Linear Derating Factor	2.0	W/°C
V_{GS}	Gate-to-Source Voltage	± 20	V
E_{AS}	Single Pulse Avalanche Energy (Thermally Limited) ③	230	mJ
I_{AR}	Avalanche Current ②	See Fig.14, 15, 18a, 18b	A
E_{AR}	Repetitive Avalanche Energy		mJ
dv/dt	Peak Diode Recovery ④	1.6	V/ns
T_J	Operating Junction and	-55 to + 175	°C
T_{STG}	Storage Temperature Range		
	Soldering Temperature, for 10 seconds (1.6mm from case)		

Thermal Resistance

Symbol	Parameter	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case ⑨	—	0.50	°C/W
$R_{\theta JA}$	Junction-to-Ambient ⑩	—	40	

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*Qualification standards can be found at www.infineon.com

Static @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(\text{BR})\text{DSS}}$	Drain-to-Source Breakdown Voltage	24	—	—	V	$V_{GS} = 0V, I_D = 250\mu\text{A}$
$\Delta V_{(\text{BR})\text{DSS}}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	0.023	—	V/ $^\circ\text{C}$	Reference to $25^\circ\text{C}, I_D = 5\text{mA}$ ⑤
$R_{DS(\text{on})}$	Static Drain-to-Source On-Resistance	—	0.80	1.0	$\text{m}\Omega$	$V_{GS} = 10V, I_D = 160\text{A}$ ⑤
$V_{GS(\text{th})}$	Gate Threshold Voltage	2.0	—	4.0	V	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$
g_{fs}	Forward Trans conductance	190	—	—	S	$V_{DS} = 15V, I_D = 160\text{A}$
R_G	Gate Resistance	—	3.0	—	Ω	
I_{DSS}	Drain-to-Source Leakage Current	—	—	20	μA	$V_{DS} = 24V, V_{GS} = 0V$
		—	—	250		$V_{DS} = 19V, V_{GS} = 0V, T_J = 125^\circ\text{C}$
I_{GSS}	Gate-to-Source Forward Leakage	—	—	200	nA	$V_{GS} = 20V$
	Gate-to-Source Reverse Leakage	—	—	-200		$V_{GS} = -20V$

Dynamic Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

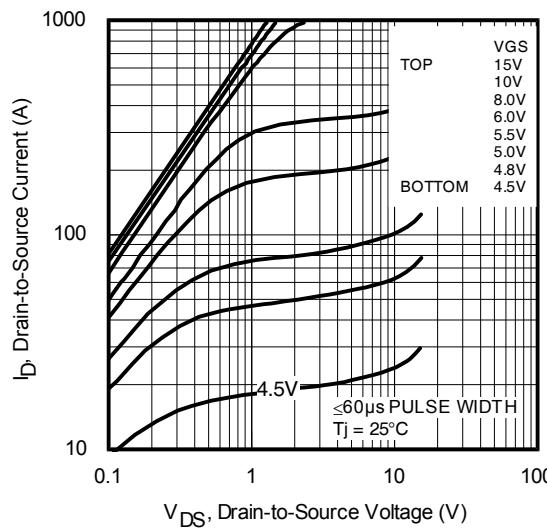
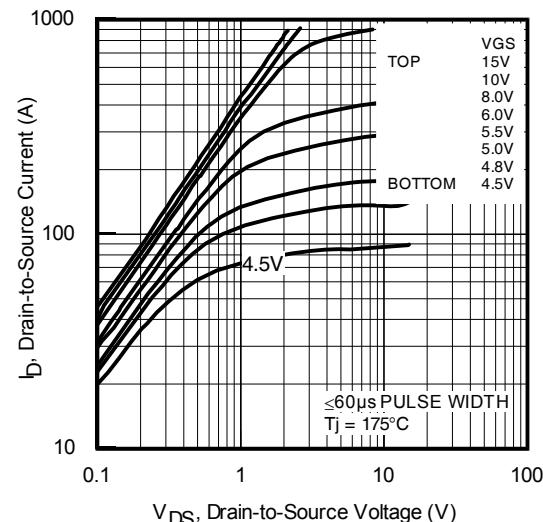
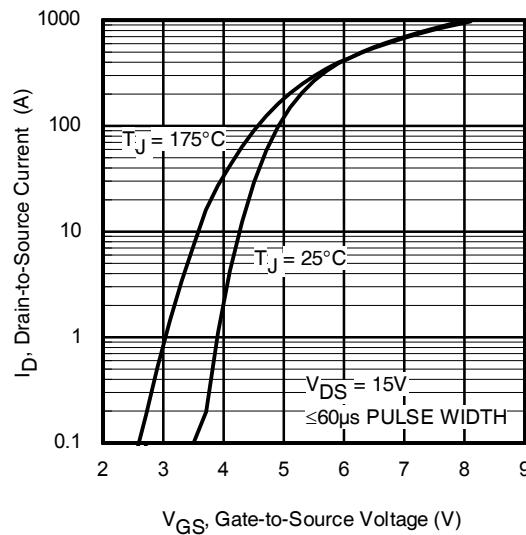
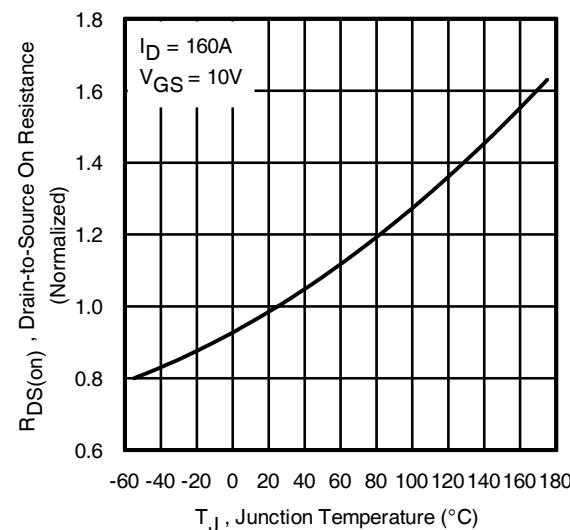
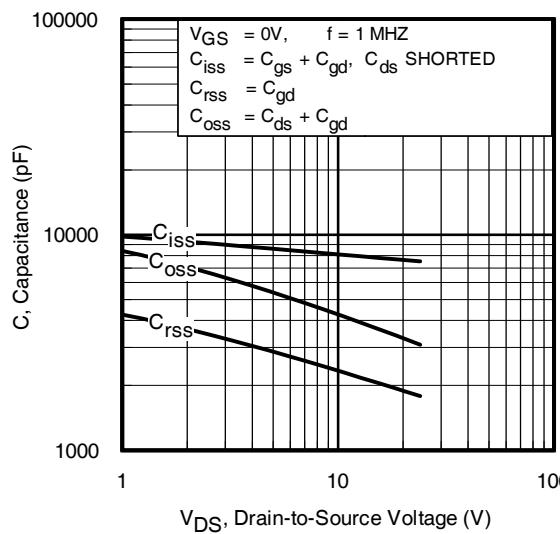
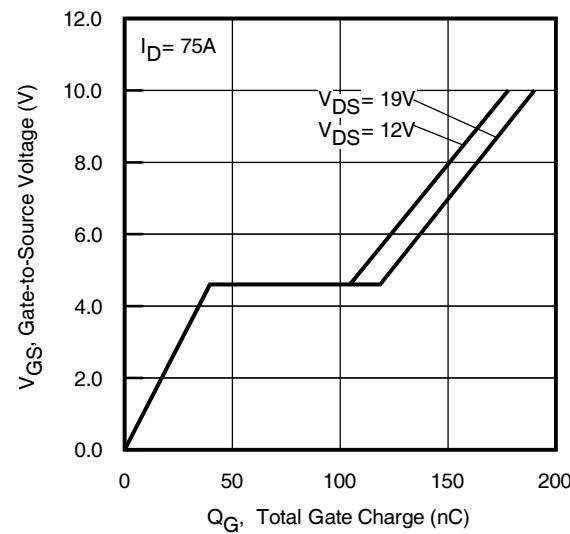
Q_g	Total Gate Charge	—	180	252	nC	$I_D = 75\text{A}$ $V_{DS} = 12V$ $V_{GS} = 10V$ ⑤
Q_{gs}	Gate-to-Source Charge	—	47	—		
Q_{gd}	Gate-to-Drain Charge	—	58	—		
Q_{sync}	Total Gate Charge Sync. ($Q_g - Q_{gd}$)	—	122	—		
$t_{d(on)}$	Turn-On Delay Time	—	19	—	ns	$V_{DD} = 16V$ $I_D = 160\text{A}$ $R_G = 2.7\Omega$ $V_{GS} = 10V$ ⑤
t_r	Rise Time	—	240	—		
$t_{d(off)}$	Turn-Off Delay Time	—	86	—		
t_f	Fall Time	—	93	—		
C_{iss}	Input Capacitance	—	7700	—	pF	$V_{GS} = 0V$ $V_{DS} = 19V$
C_{oss}	Output Capacitance	—	3380	—		
C_{rss}	Reverse Transfer Capacitance	—	1930	—		$f = 1.0\text{MHz}$, See Fig. 5
$C_{oss \text{ eff. (ER)}}$	Effective Output Capacitance (Energy Related)	—	4780	—		$V_{GS} = 0V, V_{DS} = 0V \text{ to } 19V$ ⑦
$C_{oss \text{ eff. (TR)}}$	Effective Output Capacitance (Time Related)	—	4970	—		$V_{GS} = 0V, V_{DS} = 0V \text{ to } 19V$ ⑥

Diode Characteristics

	Parameter	Min.	Typ.	Max.	Units	Conditions
I_S	Continuous Source Current (Body Diode)	—	—	429 ①	A	MOSFET symbol showing the integral reverse p-n junction diode.
I_{SM}	Pulsed Source Current (Body Diode) ②	—	—	1640		
V_{SD}	Diode Forward Voltage	—	—	1.3	V	$T_J = 25^\circ\text{C}, I_S = 160\text{A}, V_{GS} = 0V$ ⑤
t_{rr}	Reverse Recovery Time	—	71	107	ns	$T_J = 25^\circ\text{C}$ $V_{DD} = 20V$
		—	74	110		$T_J = 125^\circ\text{C}$ $I_F = 160\text{A}$,
Q_{rr}	Reverse Recovery Charge	—	83	120	nC	$T_J = 25^\circ\text{C}$ $di/dt = 100\text{A}/\mu\text{s}$ ⑤
		—	92	140		$T_J = 125^\circ\text{C}$
I_{RRM}	Reverse Recovery Current	—	2.0	—	A	$T_J = 25^\circ\text{C}$
t_{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by $L_s + L_D$)				

Notes:

- ① Calculated continuous current based on maximum allowable junction temperature. Bond wire current limit is 240A. Note that current limitations arising from heating of the device leads may occur with some lead mounting arrangements.
- ② Repetitive rating; pulse width limited by max. junction temperature.
- ③ Limited by $T_{J\text{max}}$, starting $T_J = 25^\circ\text{C}$, $L = 0.018\text{mH}$, $R_G = 25\Omega$, $I_{AS} = 160\text{A}$, $V_{GS} = 10V$. Part not recommended for use above this value.
- ④ $I_{SD} \leq 160\text{A}$, $di/dt \leq 600\text{A}/\mu\text{s}$, $V_{DD} \leq V_{(\text{BR})\text{DSS}}$, $T_J \leq 175^\circ\text{C}$.
- ⑤ Pulse width $\leq 400\mu\text{s}$; duty cycle $\leq 2\%$.
- ⑥ $C_{oss \text{ eff. (TR)}}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS} .
- ⑦ $C_{oss \text{ eff. (ER)}}$ is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS} .
- ⑧ When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994
- ⑨ R_θ is measured at T_J approximately 90°C .


Fig. 1 Typical Output Characteristics

Fig. 2 Typical Output Characteristics

Fig. 3 Typical Transfer Characteristics

Fig. 4 Normalized On-Resistance vs. Temperature

Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage

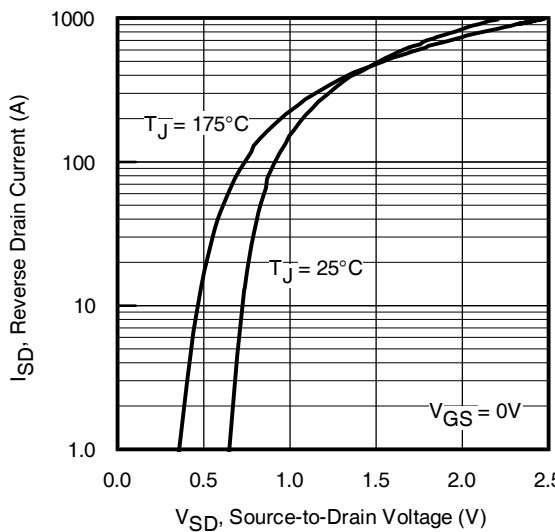


Fig. 7 Typical Source-to-Drain Diode Forward Voltage

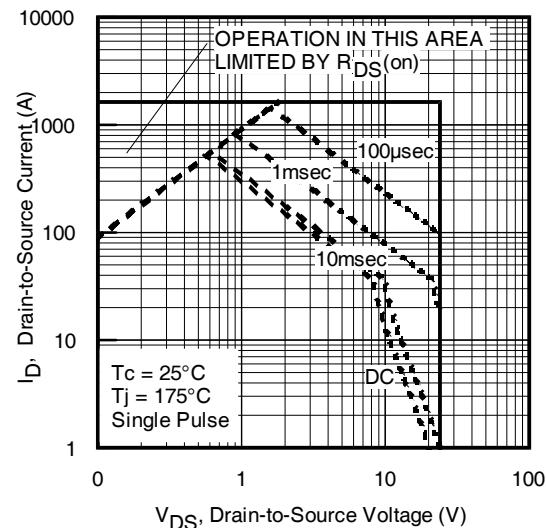


Fig 8. Maximum Safe Operating Area

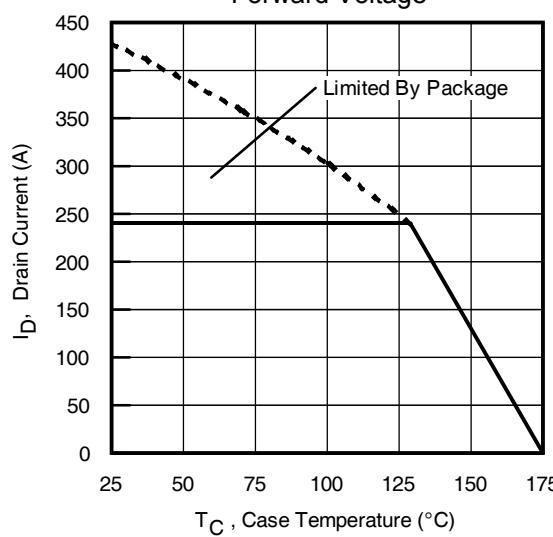


Fig 9. Maximum Drain Current vs. Case Temperature

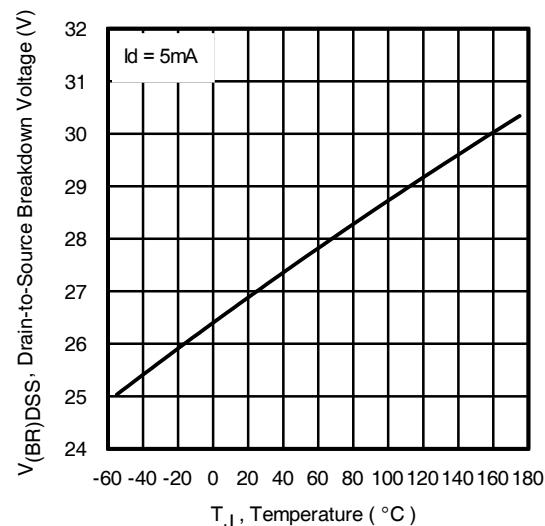


Fig 10. Drain-to-Source Breakdown Voltage

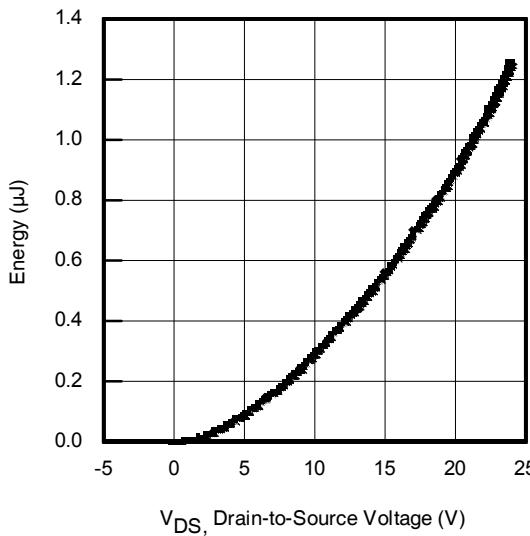


Fig 11. Typical Coss Stored Energy

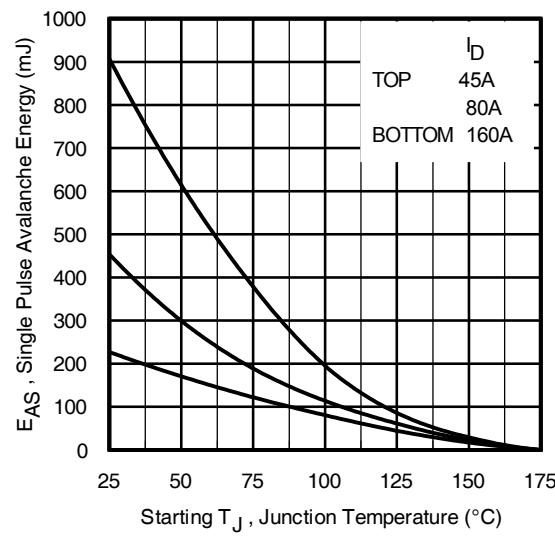


Fig 12. Maximum Avalanche Energy vs. Drain Current

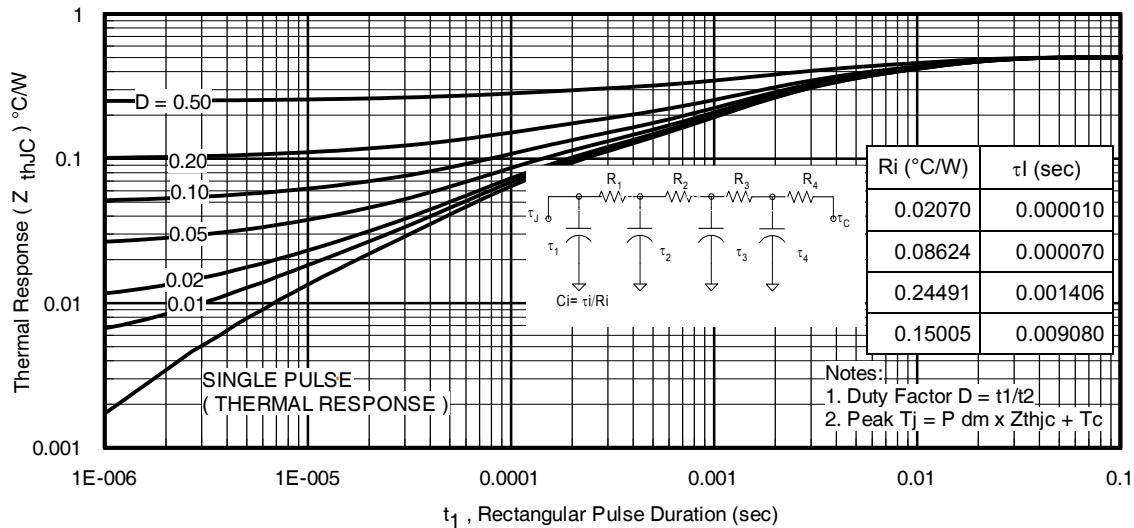


Fig 13. Maximum Effective Transient Thermal Impedance, Junction-to-Case

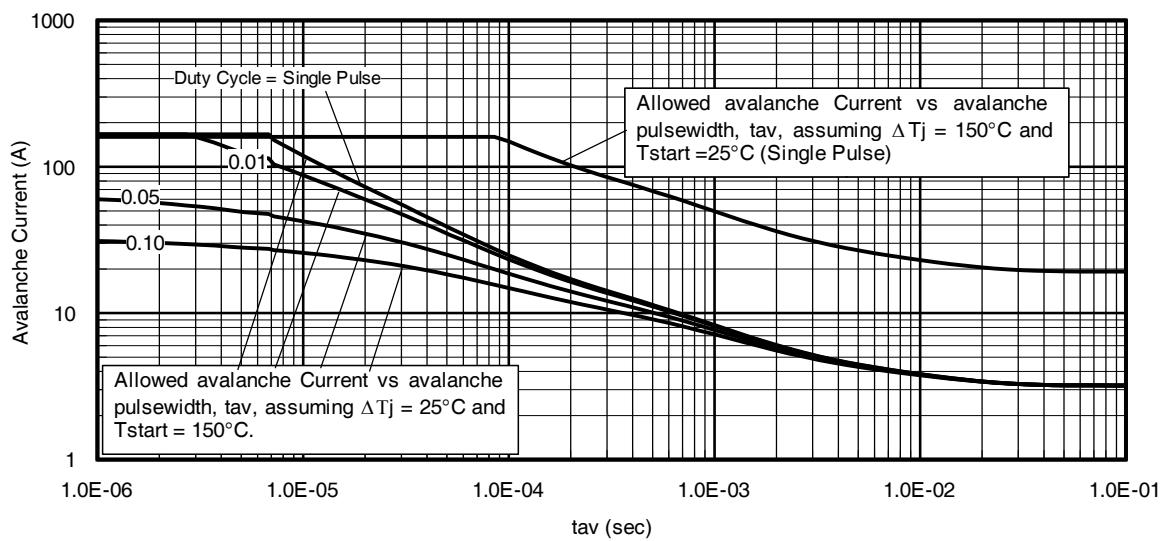


Fig 14. Avalanche Current vs. Pulse width

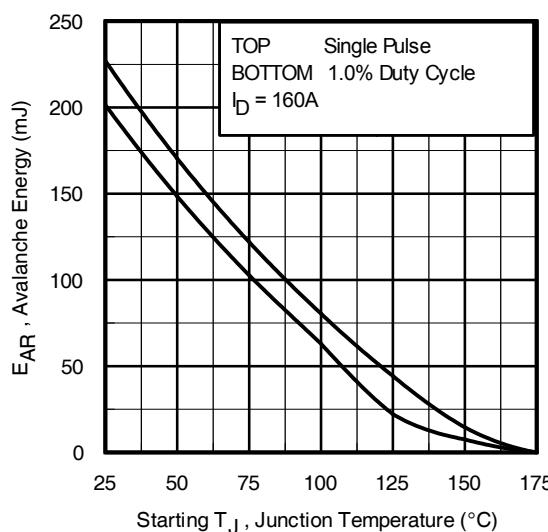


Fig 15. Maximum Avalanche Energy vs. Temperature

Notes on Repetitive Avalanche Curves , Figures 14, 15:

(For further info, see AN-1005 at www.infineon.com)

1. Avalanche failures assumption:
Purely a thermal phenomenon and failure occurs at a temperature far in excess of $T_{j\max}$. This is validated for every part type.
 2. Safe operation in Avalanche is allowed as long as $T_{j\max}$ is not exceeded.
 3. Equation below based on circuit and waveforms shown in Figures 18a, 18b.
 4. $P_{\text{D}(\text{ave})}$ = Average power dissipation per single avalanche pulse.
 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
 6. I_{av} = Allowable avalanche current.
 7. ΔT = Allowable rise in junction temperature, not to exceed $T_{j\max}$ (assumed as 25°C in Figure 13, 14).
- t_{av} = Average time in avalanche.
 D = Duty cycle in avalanche = $t_{\text{av}} \cdot f$
 $Z_{\text{thJC}}(D, t_{\text{av}})$ = Transient thermal resistance, see Figures 13)

$$P_{\text{D}(\text{ave})} = 1/2 (1.3 \cdot \text{BV} \cdot I_{\text{av}}) = \Delta T / Z_{\text{thJC}}$$

$$I_{\text{av}} = 2\Delta T / [1.3 \cdot \text{BV} \cdot Z_{\text{th}}]$$

$$E_{\text{AS(AR)}} = P_{\text{D}(\text{ave})} \cdot t_{\text{av}}$$

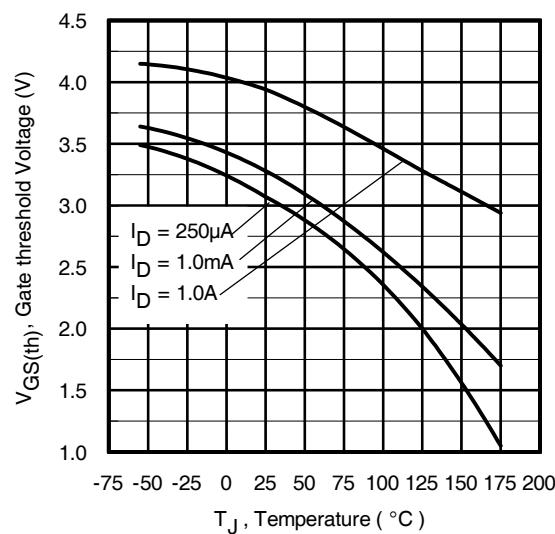


Fig 16. Threshold Voltage vs. Temperature

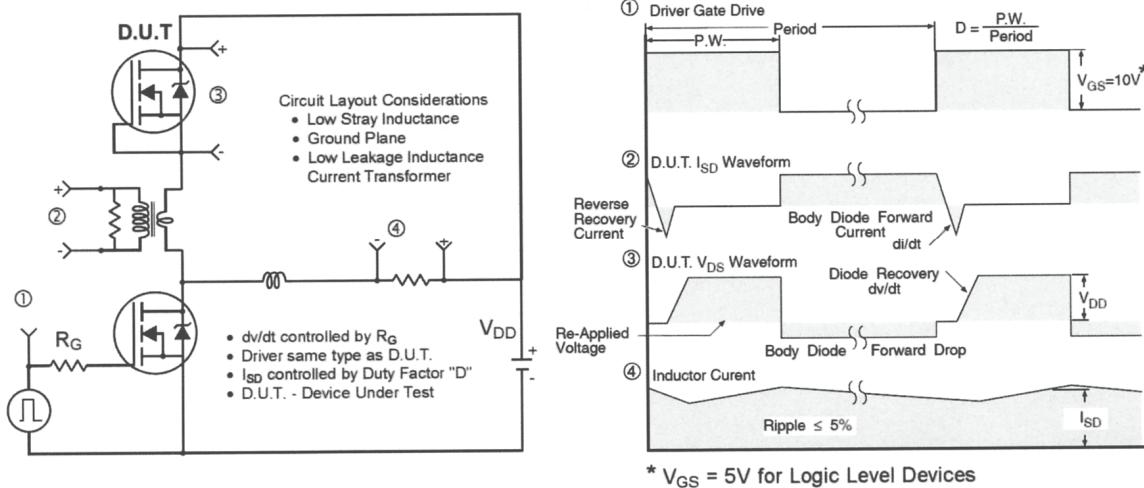


Fig 17. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

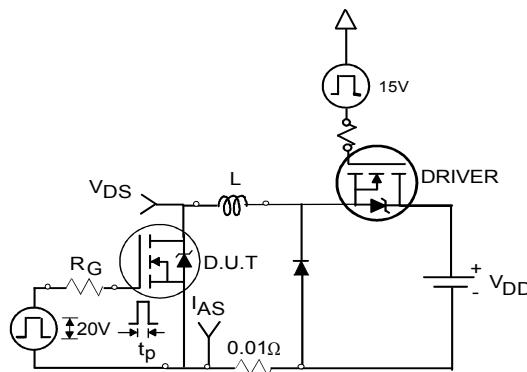


Fig 18a. Unclamped Inductive Test Circuit

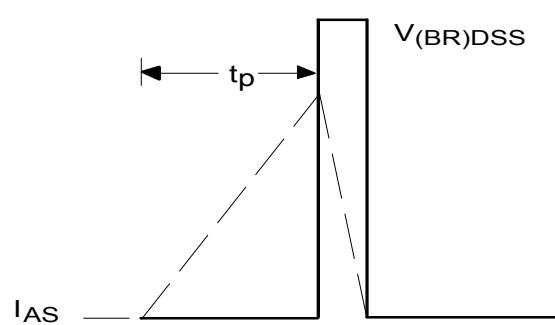


Fig 18b. Unclamped Inductive Waveforms

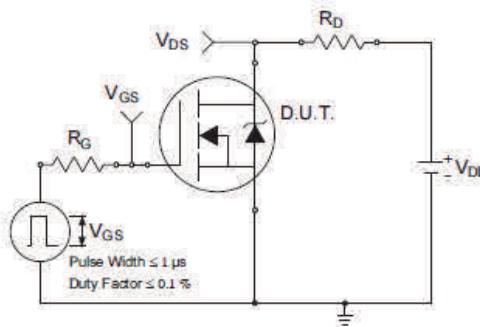


Fig 19a. Switching Time Test Circuit

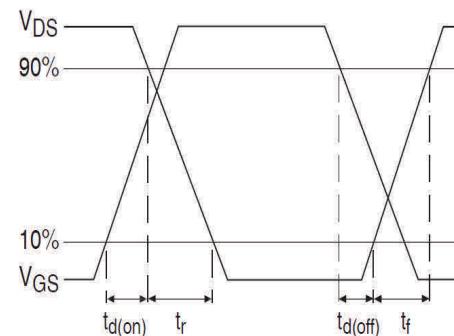


Fig 19b. Switching Time Waveforms

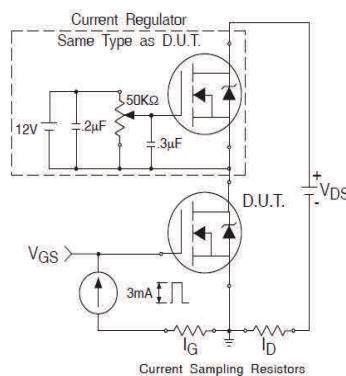


Fig 20a. Gate Charge Test Circuit

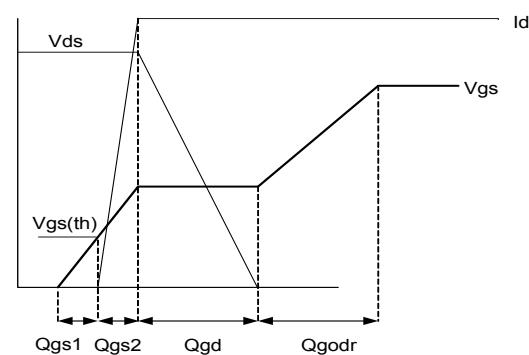
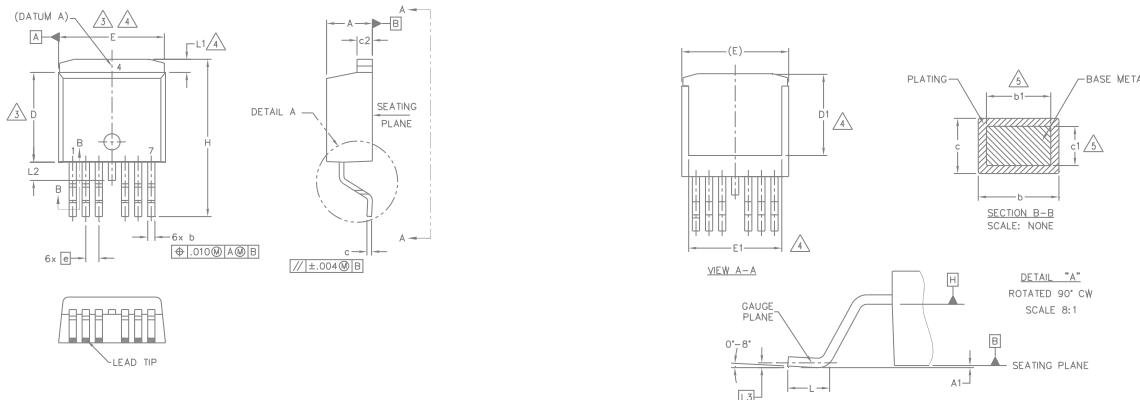


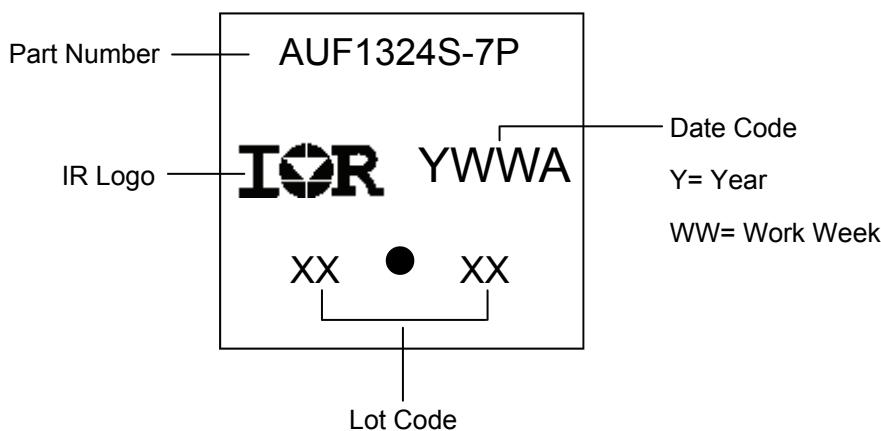
Fig 20b. Gate Charge Waveform

D²Pak - 7 Pin Package Outline (Dimensions are shown in millimeters (inches))

S Y M B O L	DIMENSIONS				N O T E S	
	MILLIMETERS		INCHES			
	MIN.	MAX.	MIN.	MAX.		
A	4.06	4.83	.160	.190		
A1	—	0.254	—	.010		
b	0.51	0.99	.020	.036	5	
b1	0.51	0.89	.020	.032		
c	0.38	0.74	.015	.029		
c1	0.38	0.58	.015	.023		
c2	1.14	1.65	.045	.065		
D	8.38	9.65	.330	.380	3	
D1	6.86	7.42	.270	.292		
E	9.65	10.54	.380	.415		
E1	6.22	8.48	.245	.334		
e	1.27 BSC		.050 BSC		4	
H	14.61	15.88	.575	.625		
L	1.78	2.79	.070	.110		
L1	—	1.68	—	.066		
L2	—	1.78	—	.070	4	
L3	0.25 BSC		.010 BSC			

NOTES:

1. DIMENSIONING AND TOLERANCING AS PER ASME Y14.5M-1994
2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
3. DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.
4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.
5. DIMENSION b1 AND c1 APPLY TO BASE METAL ONLY.
6. DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
7. CONTROLLING DIMENSION: INCH.
8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-263CB.
EXCEPT FOR DIMS. E, E1 & D1.

D²Pak - 7 Pin Part Marking Information

Qualification Information

Qualification Level		Automotive (per AEC-Q101)	
		Comments: This part number(s) passed Automotive qualification. Infineon's Industrial and Consumer qualification level is granted by extension of the higher Automotive level.	
Moisture Sensitivity Level		D ² -Pak 7 Pin	MSL1
ESD	Machine Model	Class M4 [†] AEC-Q101-002	
	Human Body Model	Class H3A [†] AEC-Q101-001	
	Charged Device Model	Class C3 [†] AEC-Q101-005	
RoHS Compliant		Yes	

† Highest passing voltage.

Revision History

Date	Comments
9/30/2015	<ul style="list-style-type: none"> • Updated datasheet with corporate template • Corrected ordering table on page 1. • Updated typo on GFS on page 2.

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